

Modeling the limits of thermal runaway in Li-ion packs and designing tests to measure those limits

John Hewson, Randy Shurtz

Summer Ferreira, Josh Lamb, Heather Barkholtz, Lorraine Torres-Castro

Sandia National Laboratories

JANNAF meeting
December 4, 2017

SAND2017-XXXXC



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Validated reliability and safety is one of four critical challenges identified in 2013 Grid Energy Storage Strategic Plan

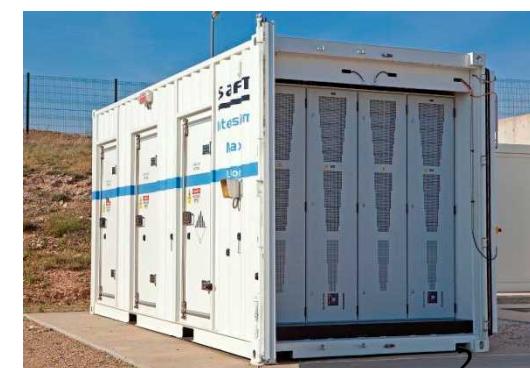
- Failure rates as low as 1 in several million,
- Potentially many cells used in energy storage.
- Moderate likelihood of 'something' going wrong,

- A single cell failure that propagates through the pack can have an impact even with low individual failure rates.

- **How do we decrease the risk?**



www.nissan.com
www.internationalbattery.com
www.samsung.com
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Approaches to designing in safety

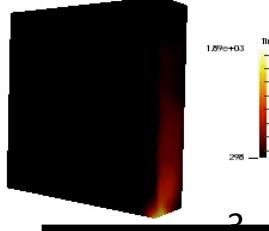
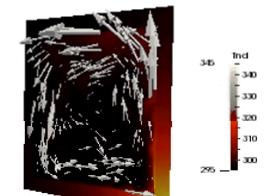
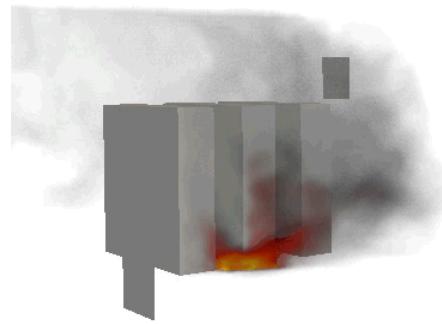
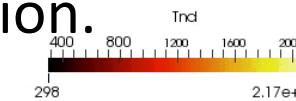
The current approach is to test our way into safety¹

- Large system (>1MWh) testing is difficult and costly.



Consider supplementing testing with predictions of challenging scenarios and optimization of mitigation.

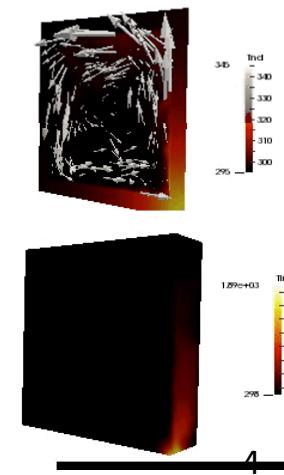
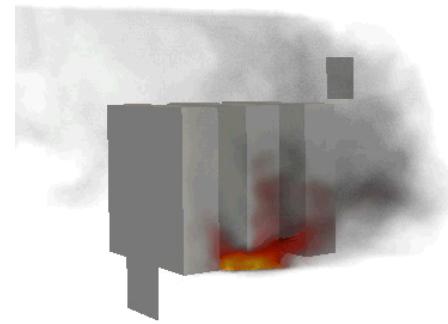
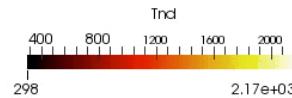
- Develop multi-physics models to predict failure mechanisms and identify mitigation.
- Build capabilities with small/medium scale measurements.
- Still requires some testing and validation.



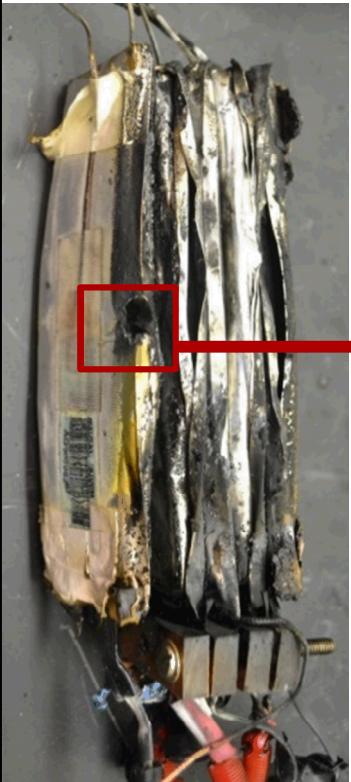
¹ 'Power Grid Energy Storage Testing Part 1.' Blume, P.; Lindenmuth, K.; Murray, J. EE – Evaluation Engineering. Nov. 2012.

A range of risks to energy storage systems

- Internal short circuit
 - Soft short—gradual discharge.
 - Hard short—sudden discharge.
- Mechanical damage,
- External heating or internal overheating.
- Overcharge.



Models for thermal runaway processes

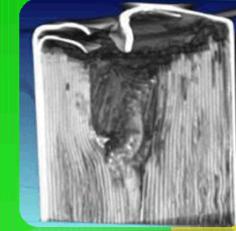


1) Simplify &
Discretize
Geometry

2) Define initial
composition, thermal
properties, reactions
(species & energy
source terms)

3) Define convection
and radiation boundary
conditions

4) Define initial
energy source



5) Calculate internal conduction and reaction rates



Models Need Parameters

- Preliminary chemistry model from literature
 - Based on Dahn group from 2000, 2001
 - Derived from calorimetry data (ARC and DSC)
 - Needs to be recalibrated—not expressed in fundamental cell characteristics.
- Empirical chemical reactions
 - SEI decomposition $2 \text{ROCO}_2\text{Li} \rightarrow \text{Li}_2\text{CO}_3 + \text{prod}$
 - Cathode-electrolyte $\text{CoO}_2 + \text{C}_3\text{H}_4\text{O}_3 \rightarrow \frac{1}{3}\text{Co}_3\text{O}_4 + \text{prod}$
 - Electrolyte-salt $\text{C}_3\text{H}_4\text{O}_3 + \text{LiPF}_6 \rightarrow \text{prod}$
 - Anode-electrolyte $\text{C}_6\text{Li} + \text{C}_3\text{H}_4\text{O}_3 \rightarrow \text{Li}_2\text{CO}_3 + \text{prod}$
- This model form has been utilized repeatedly for oven-test runaway prediction.

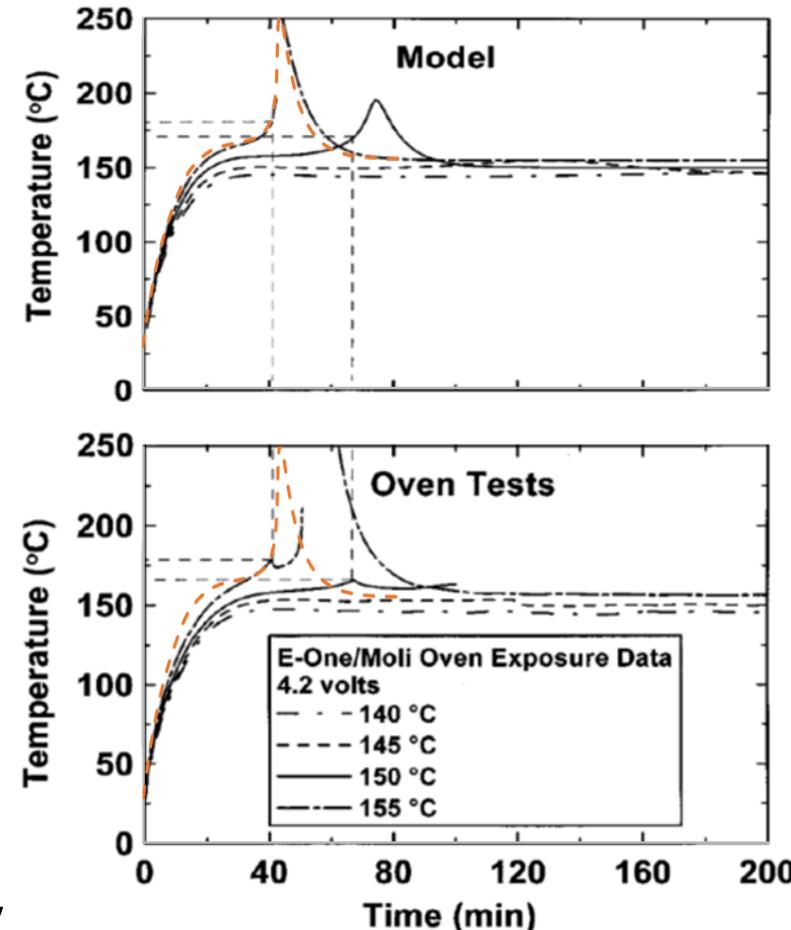
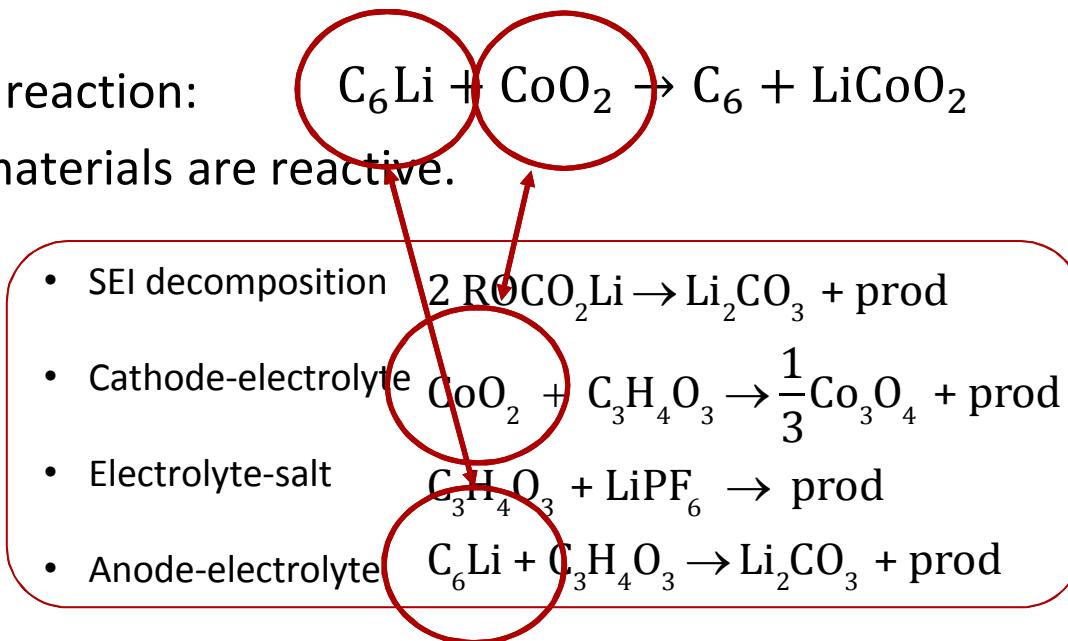


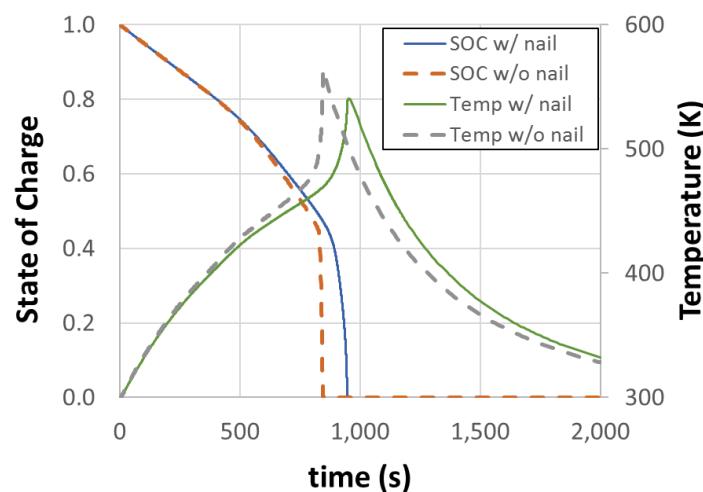
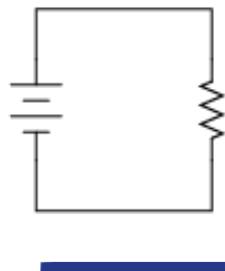
Figure 2. A comparison of oven exposure test results to model predictions: (top) model predictions and (bottom) oven test results for 18650 E-One/Moli Energy cells charged to 4.2 V.

Thermal and electrochemical reactants are same

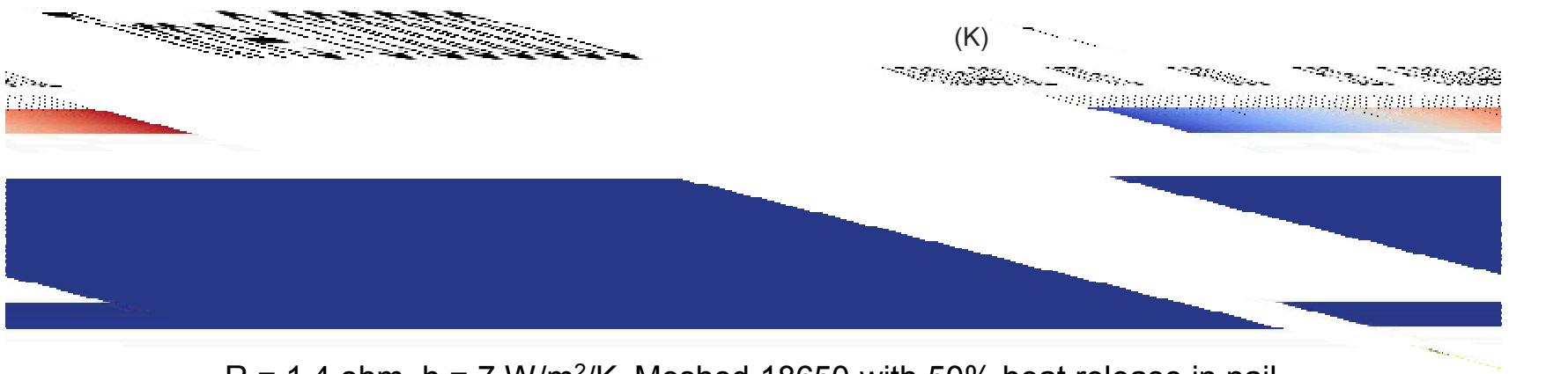
- Discharge reaction: $C_6Li + CoO_2 \rightarrow C_6 + LiCoO_2$
- Charged materials are reactive.



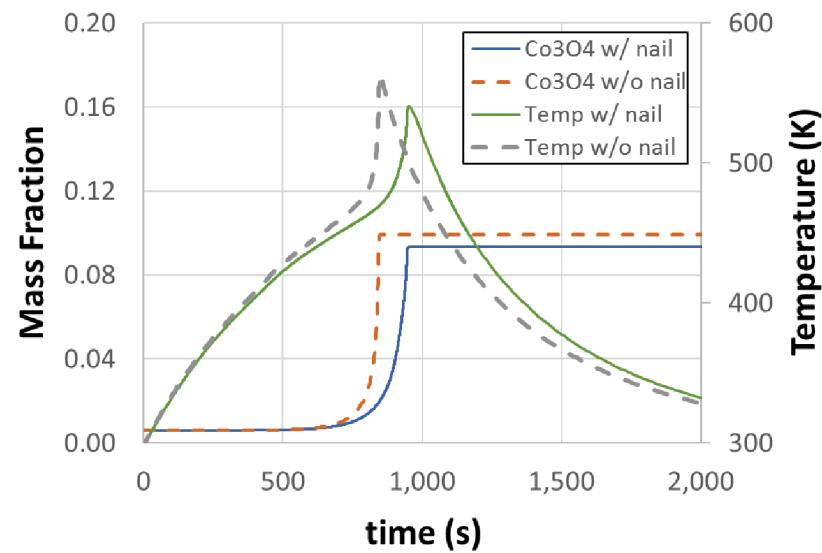
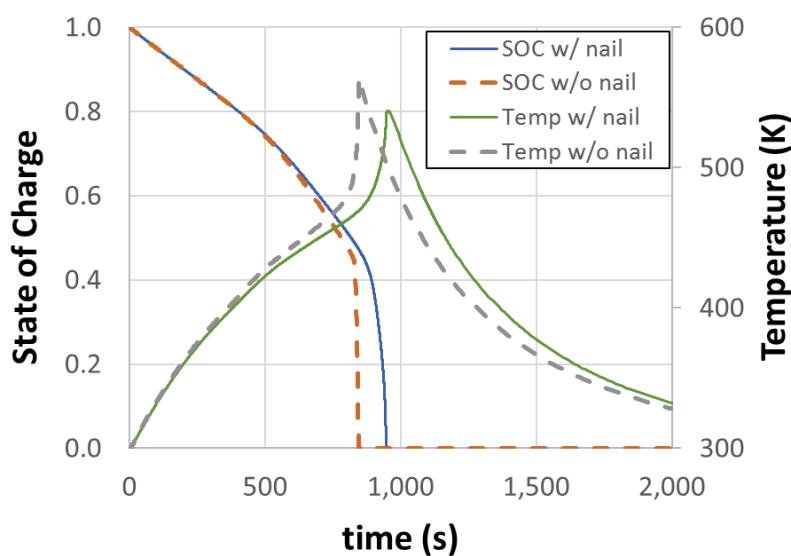
Simulated short circuit
plus thermal runaway



Short-circuit induced runaway in meshed 18650 with nail



$R = 1.4 \text{ ohm}$, $h = 7 \text{ W/m}^2/\text{K}$, Meshed 18650 with 50% heat release in nail



- Effects of inhomogeneity increase as scale increases beyond the lumped-capacitance regime.

Relative importance of short-circuit versus thermal reactions

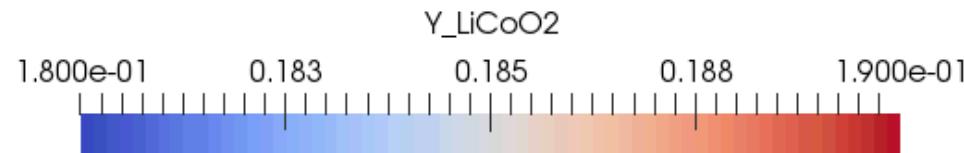
$R = 1.4 \text{ ohm}$, $h = 7 \text{ W/m}^2/\text{K}$, Meshed 18650 with 50% heat release in nail

Time: 1004.759876

Thermal Reaction Cathode Product



Short Circuit Cathode Product

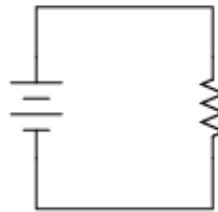


Energetics of thermal runaway in high-temperature environments and under internal short-circuits

Simulated oven test



high
temp
environ

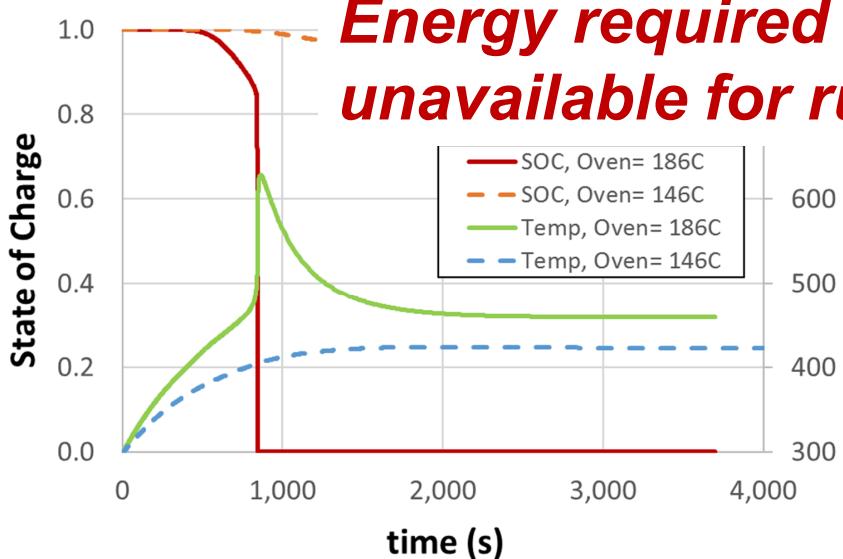


Simulated short circuit analogy with oven temperature

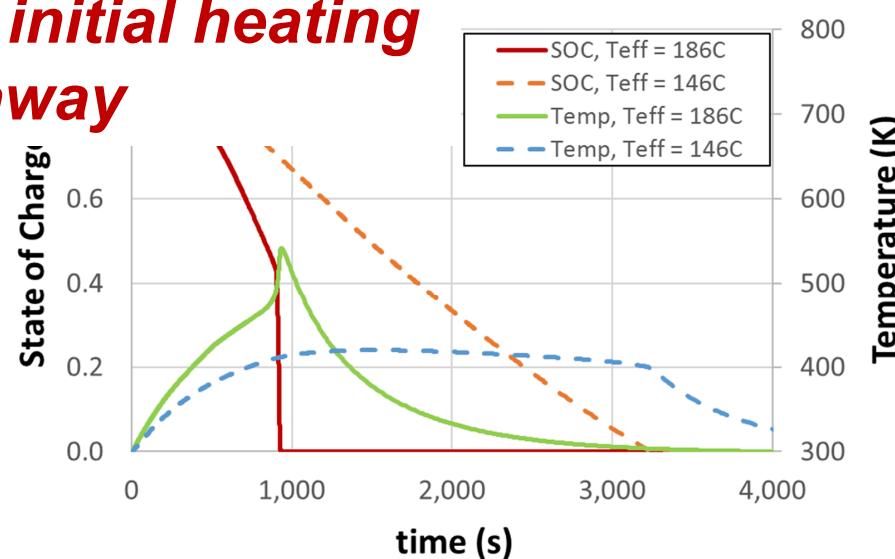


$$P = \frac{V^2}{R}$$

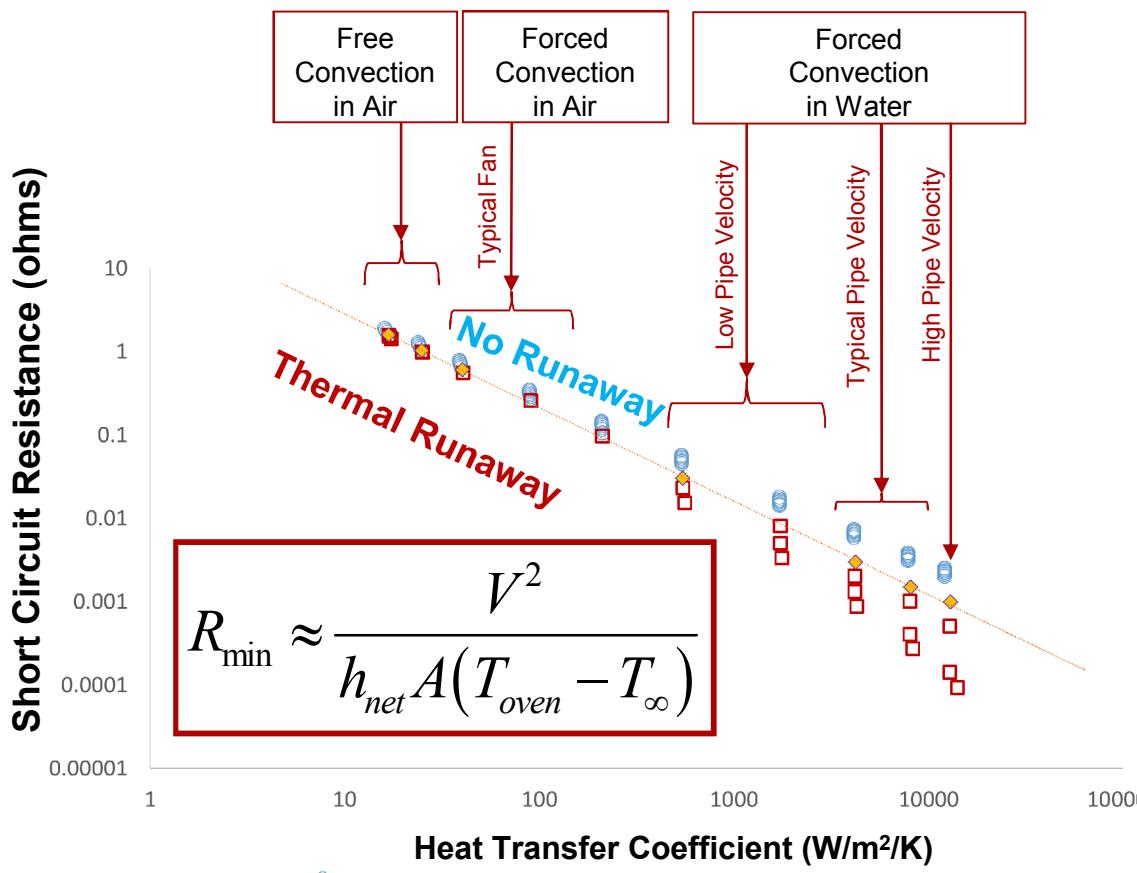
$$T_{eff} = T_{\infty} + P / h_{net} A$$



**Energy required for initial heating
unavailable for runaway**

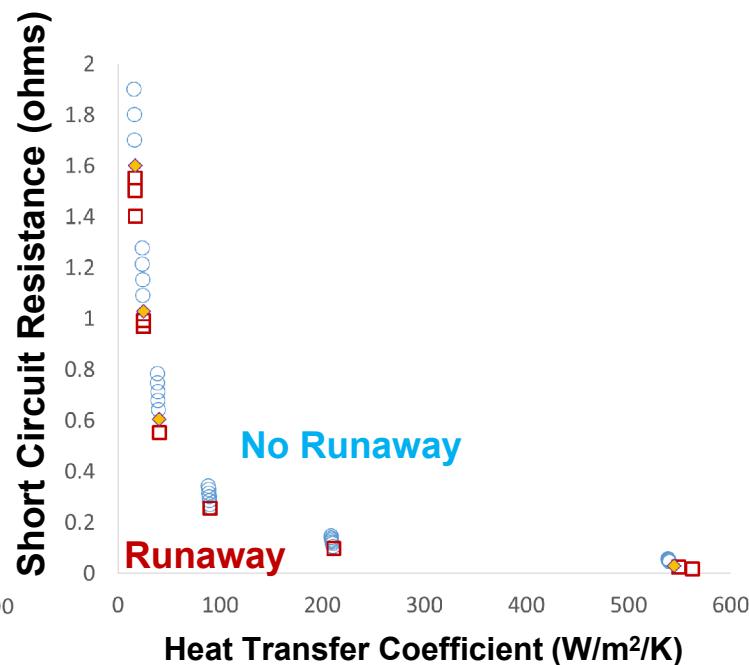


How Much Cooling to Suppress Runaway with Internal Short Circuit?



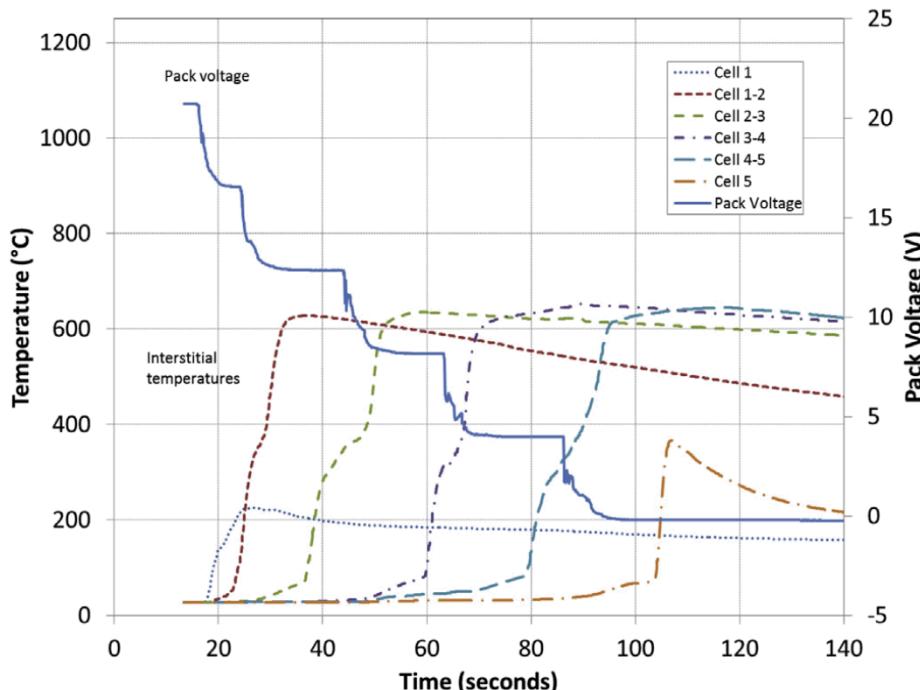
$$T_{\text{eff}} = T_{\infty} + P / h_{\text{net}} A$$

$$P = \frac{V^2}{R}$$

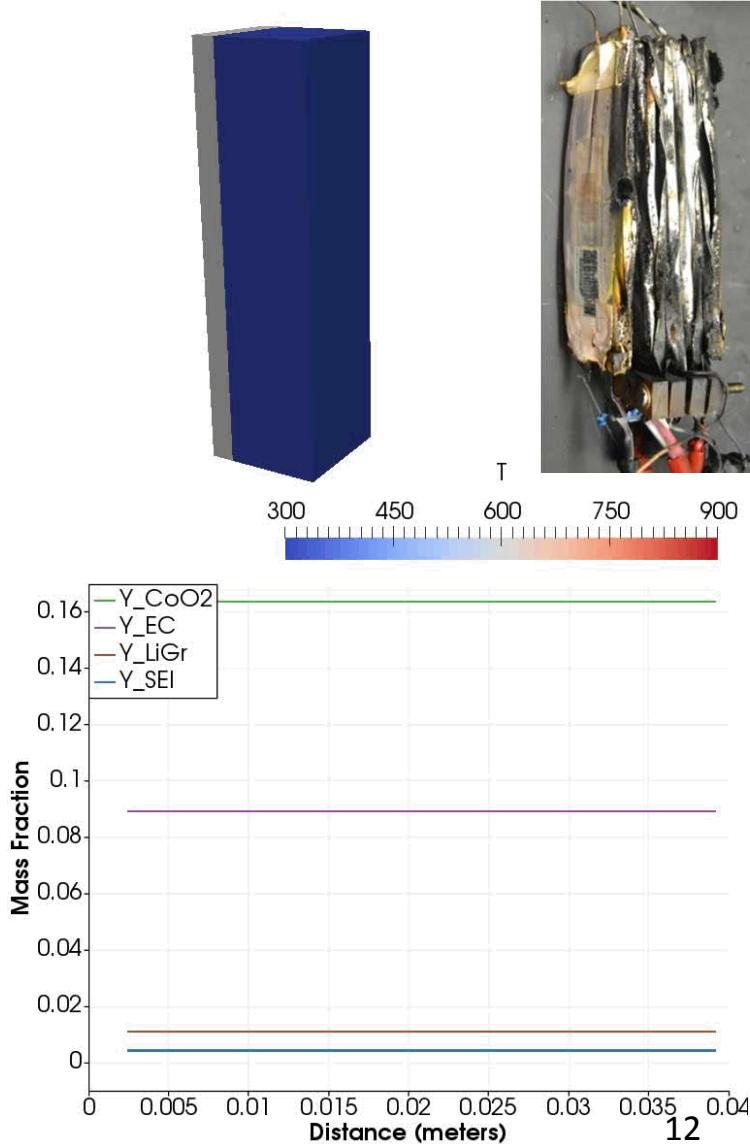


- Models can be used to estimate cooling requirements
 - Simulation shows homogeneous heating of 18650 cells (varying short resistance and cooling)
 - Internal temperature variation will be worse for large format systems and localized shorts

Cascading Propagation Observed in Li-Ion Packs

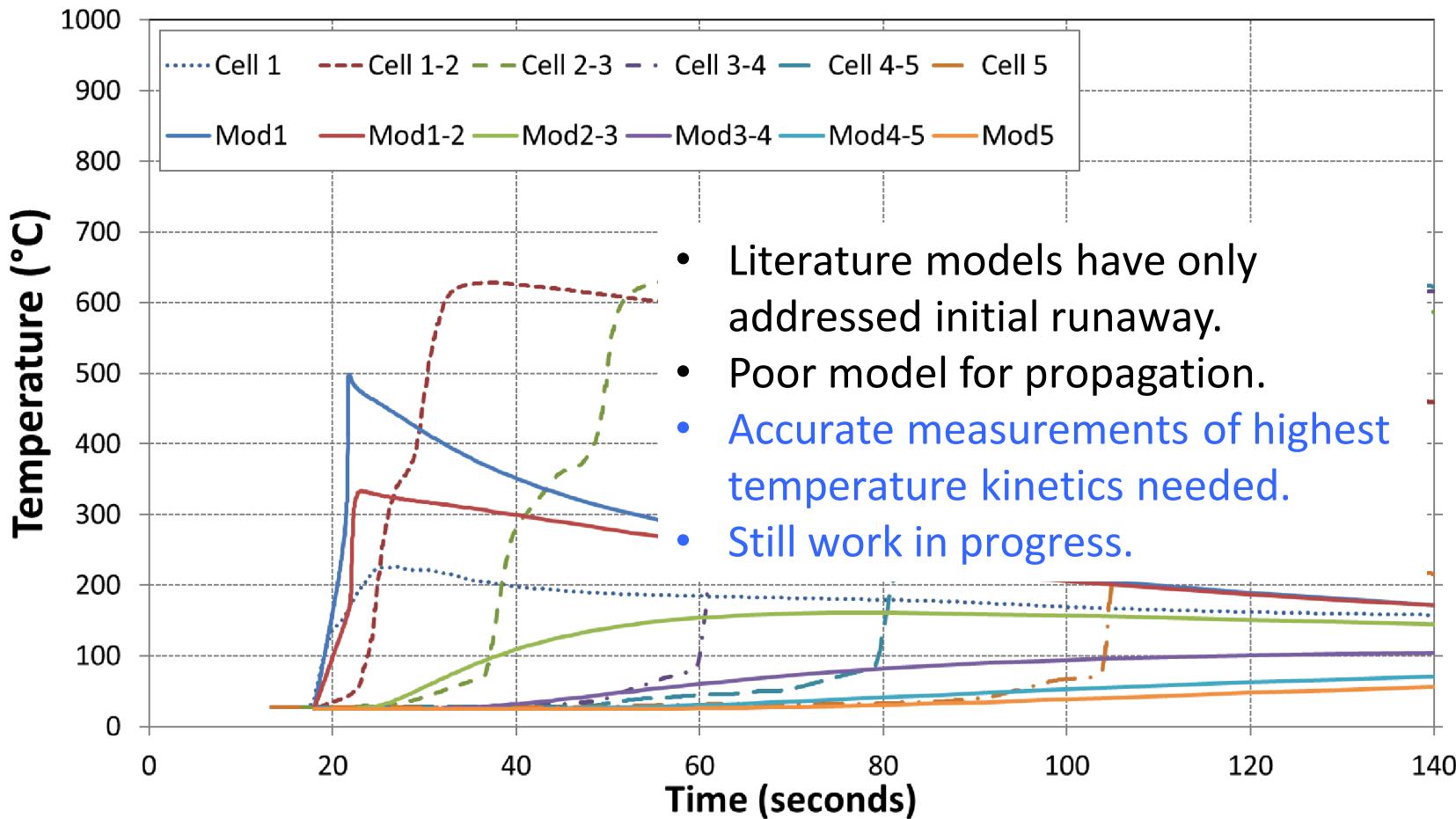


- Experimental propagation in 5 stacked pouch cells at Sandia
- Investigating effects of
 - State of charge
 - Intermediate layers
 - System geometry
- Good pack-scale model validation cases

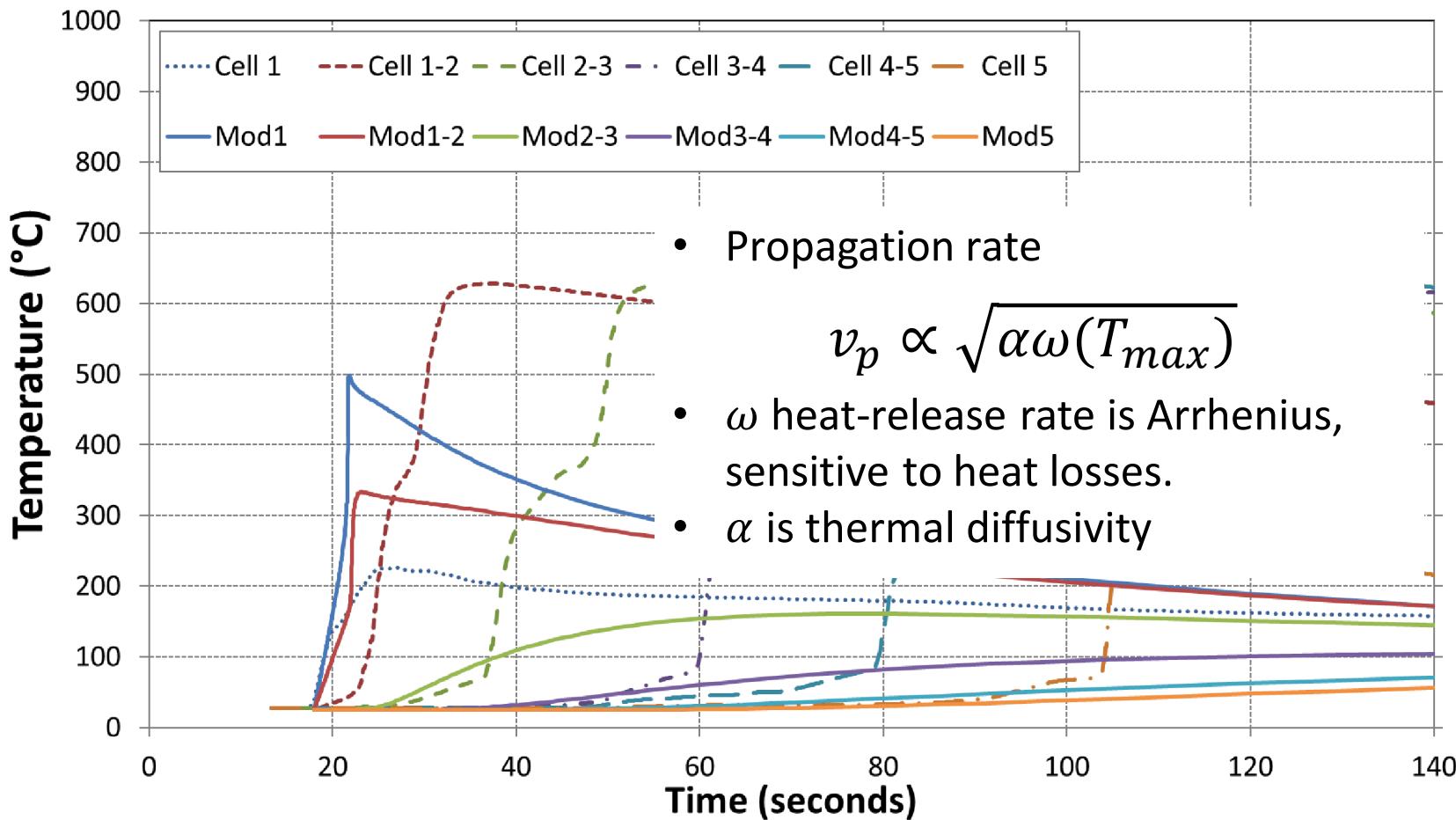


High-Fidelity Models Required for Cascading Failure

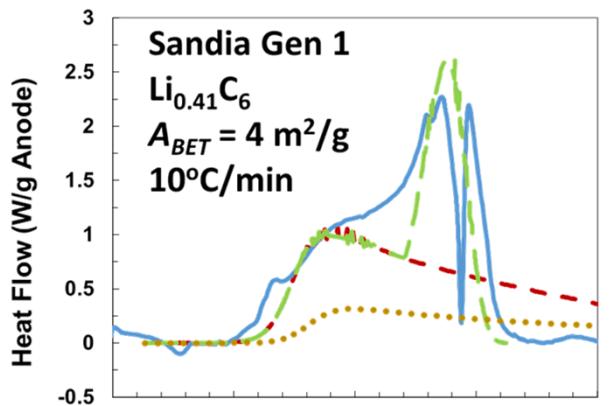
Literature Chemistry Model



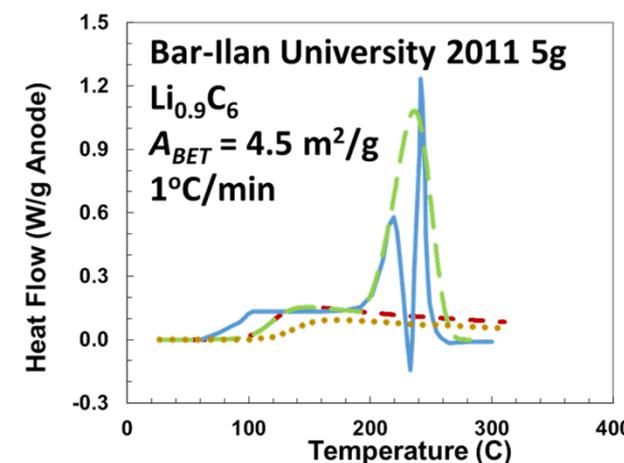
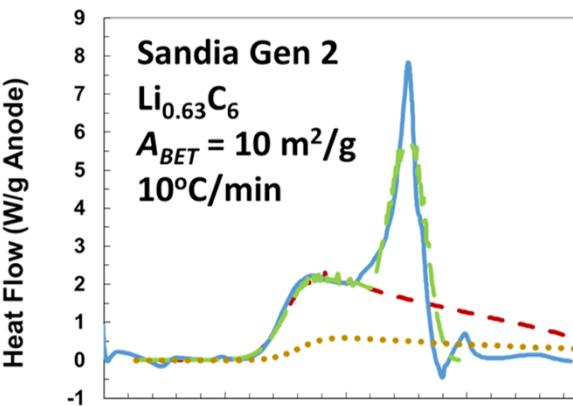
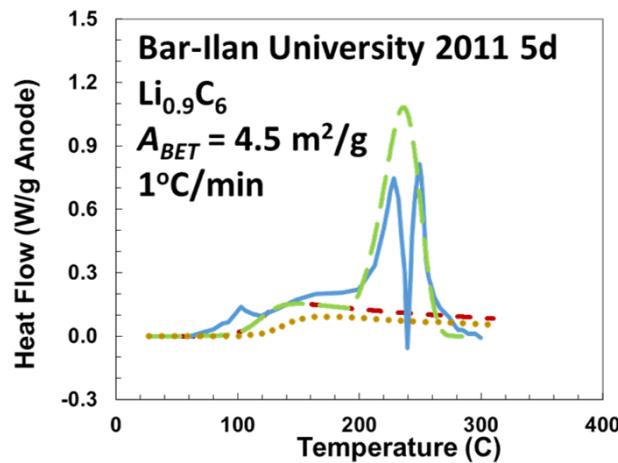
Literature Chemistry Model



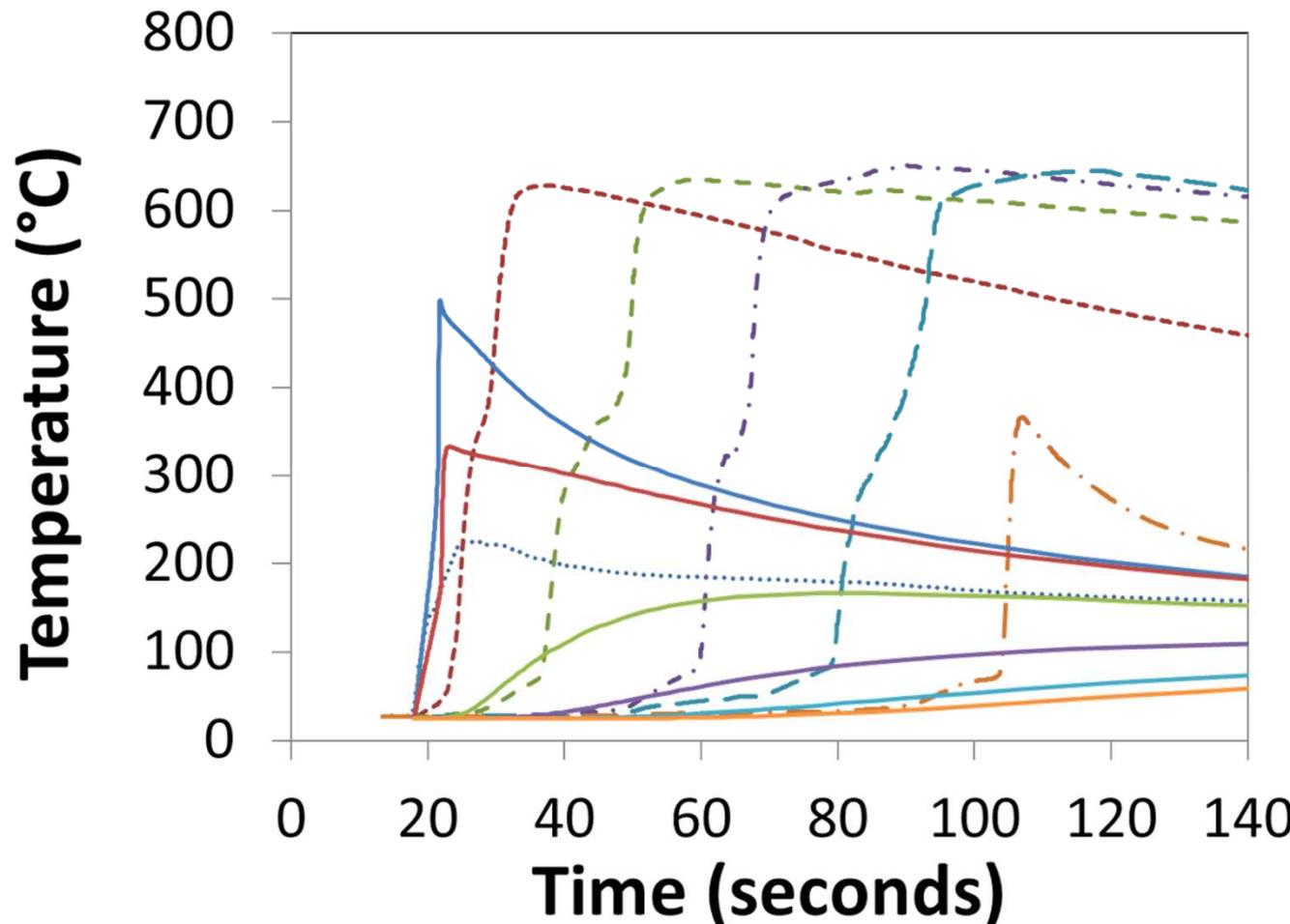
New model based on measurable quantities and thermodynamic material properties



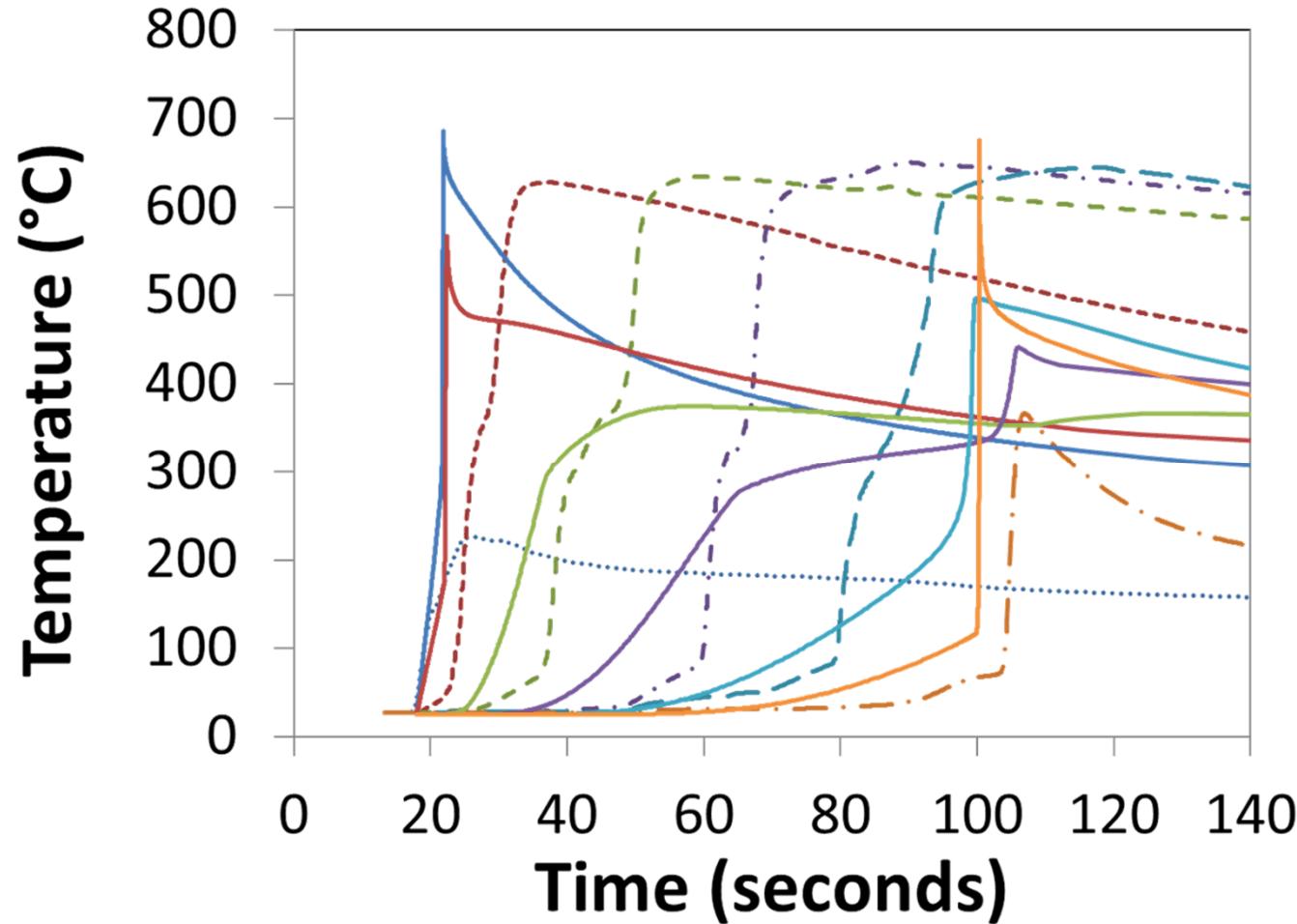
Data **Dahn Model** **Area-Scaled** **Critical Thickness**



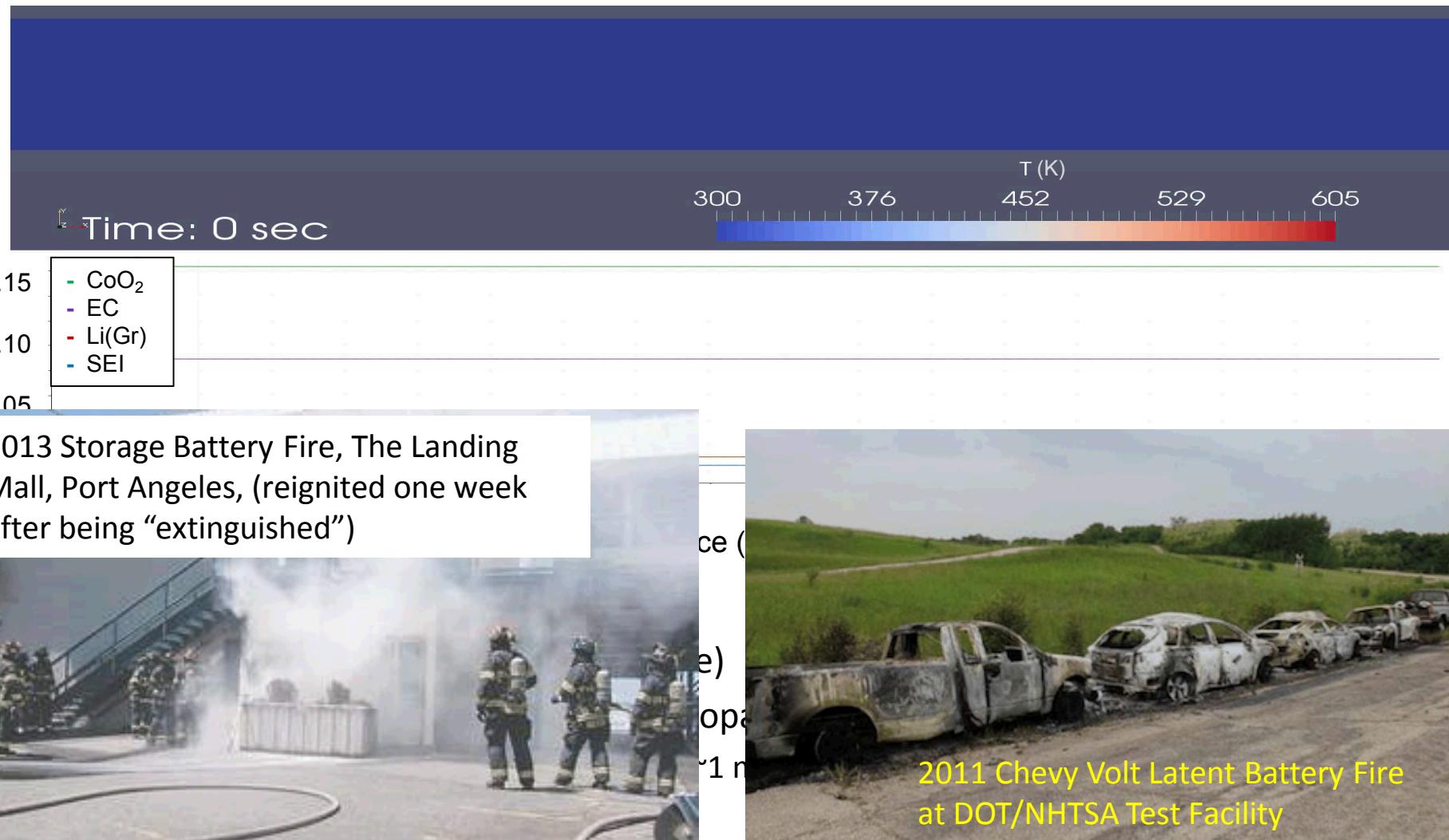
Dahn Model (Hatchard et al. 2001)



Dahn + New Anode Model, Alternate Anode Parameters



Extend modeling to Large Scales – Pulsating propagation

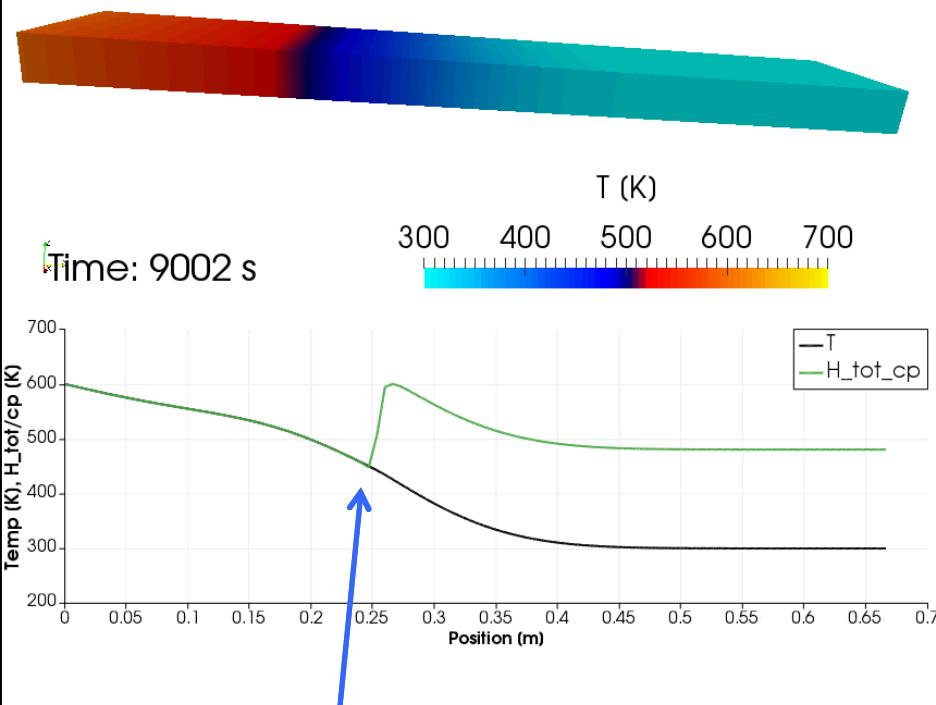


- Slow periods are best opportunity for cooling, but need to consider slow hidden reactions.

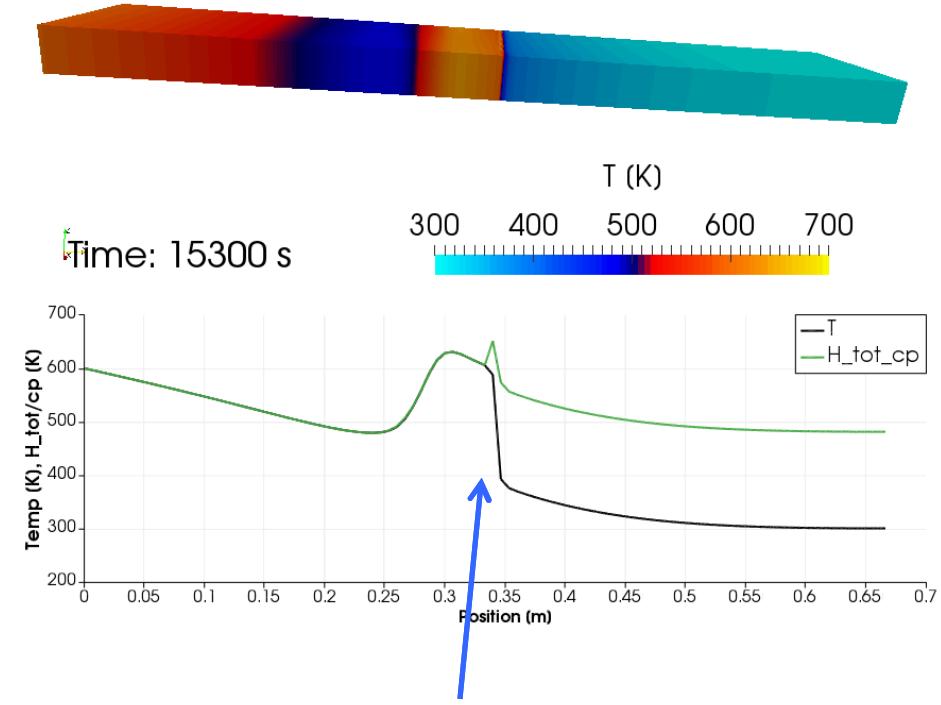


The mechanism of pulsating propagation

- Heat released is conducted upstream of reaction front, increasing the total enthalpy (sum of sensible and chemical enthalpy) $H_{TOT} = c_p T + Y_r \Delta H_r$
- Front propagates rapidly through preheated region with larger H_{TOT} .

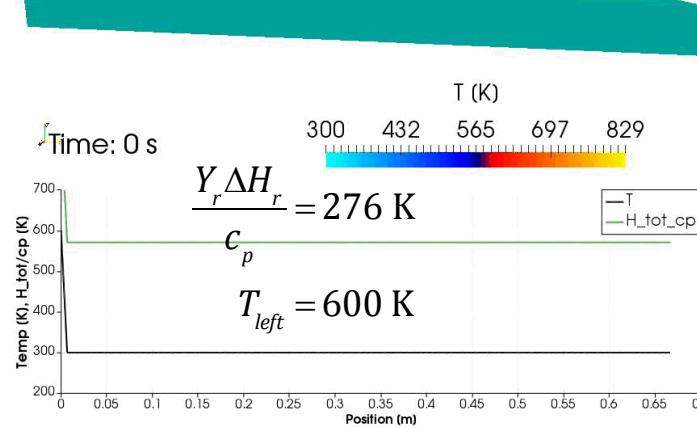
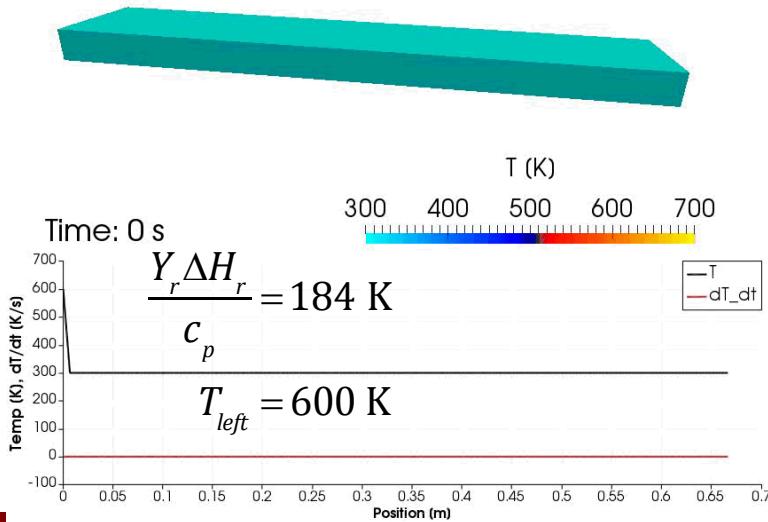
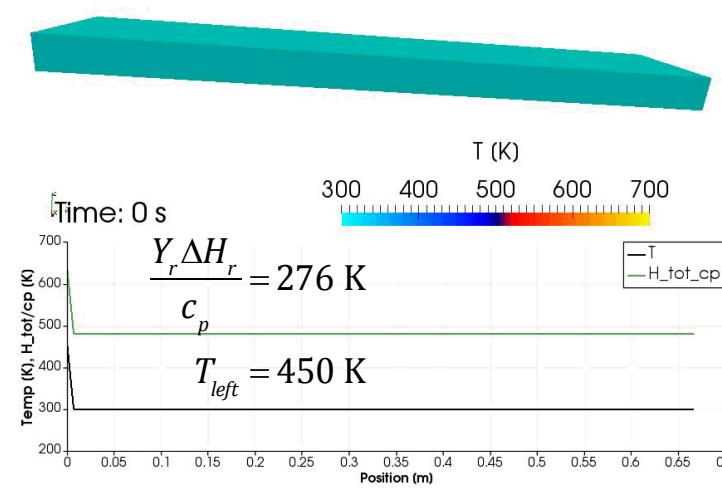
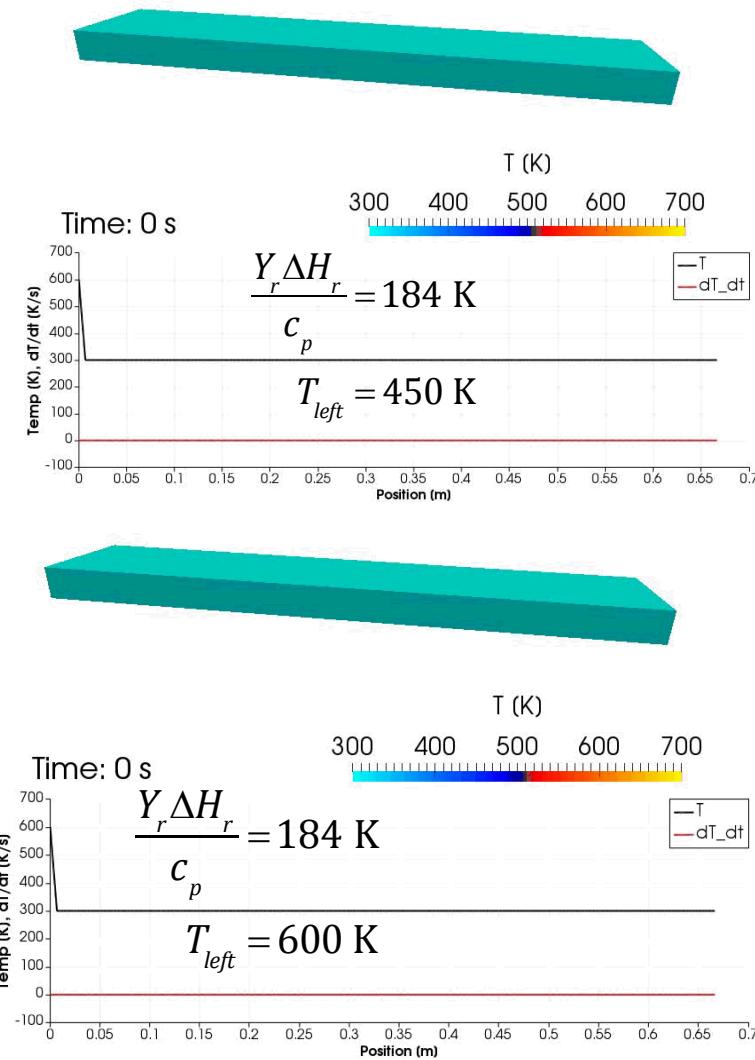


- Slow propagation (low Temp), but preheating mixture ahead of reaction front.



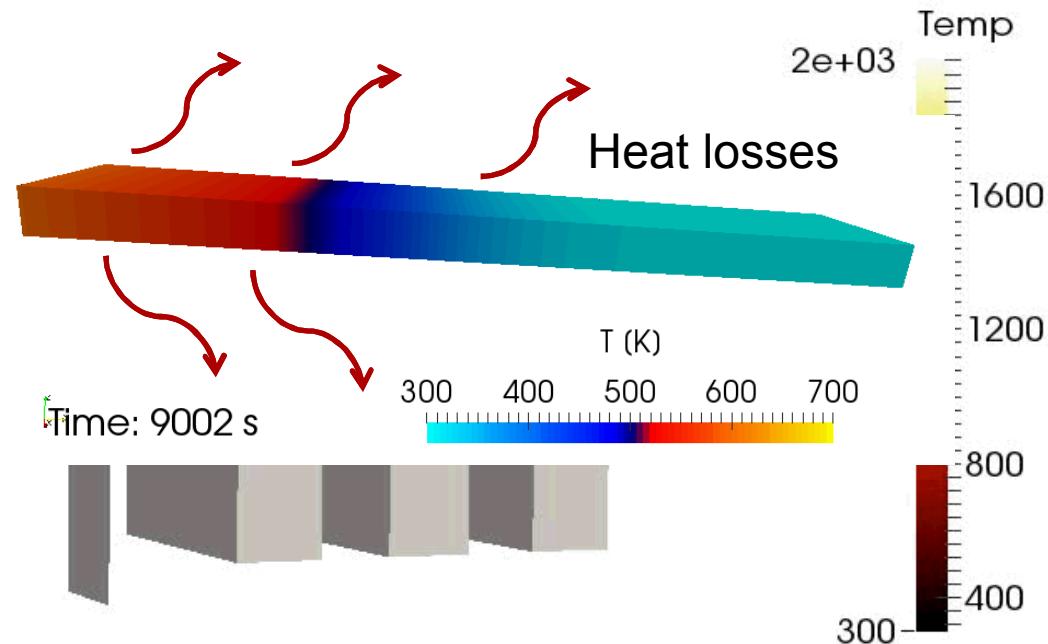
- Rapid propagation (high Temp), into preheated mixture.

Parameter studies of propagation at large scales are possible with models



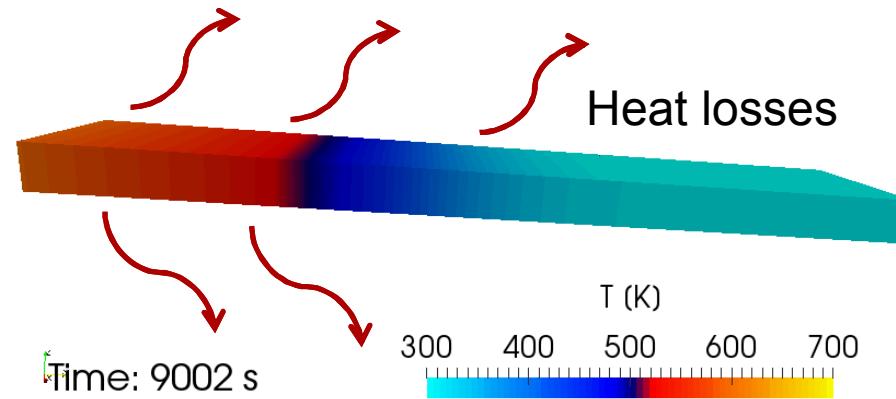
External risks to energy storage systems

- External fires:
 - Relatively low heat flux.
 - Installation integrated suppression.



Looking forward

- Thermal management can be an effective approach to managing thermal runaway risks.
- Heat capacity can inhibit ignition and propagation.
- Moderate cooling can quench propagation, and sometimes ignition.
- Simulations allow exploration of trade space if the physics are known.
 - But physics still must be observed and measured.
- → **Ultimate goal: *Predict criteria for cascading failure to act as a design tool in developing mitigation strategies.***



In closing

- Thermal runaway is a risk and potential barrier to development and acceptance.
- Heat release rates are moderate relative to potential dissipation.
- Multi-physics thermal models can potentially identify critical ignition and propagation trends.
- Quality measurements are key to parameter identification.
- Recent progress
 - Development of thermal source terms.
 - Identification of thermal ignition criterion.
 - Cell-to-cell propagation along homogenized pack structures.

Acknowledgements

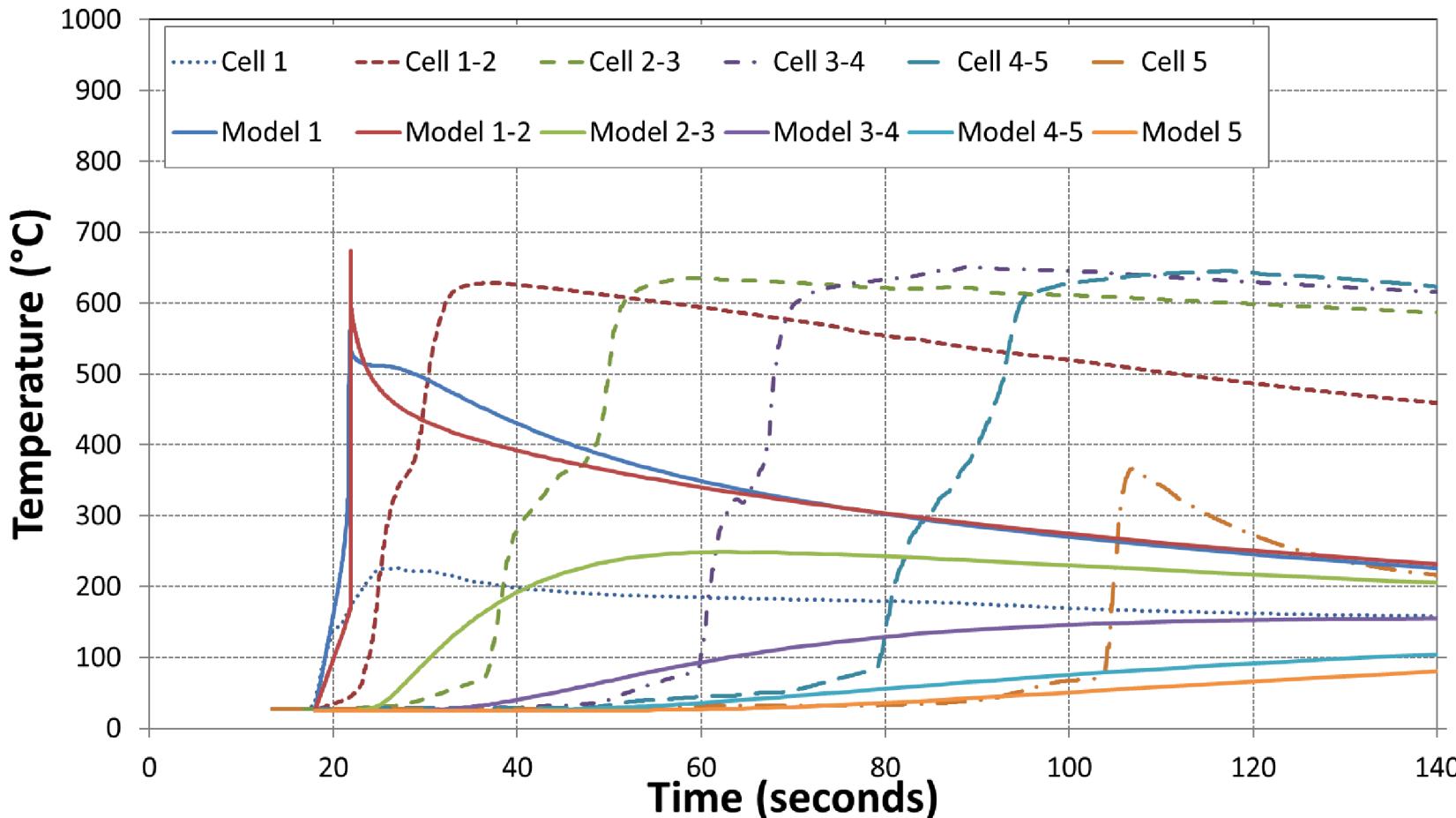
- Supported by Imre Gyuk and the OE Electrical Energy Storage Program.
- Collaborative discussions with Heather Barkholtz, Lorraine Castro, Summer Ferreira, Josh Lamb, Chris Orendorff and Dave Ingersoll have been instrumental in understanding the range of possible topics that might be addressed.

THANK YOU

QUESTIONS:
JOHN HEWSON
jchewso@sandia.gov

High-Fidelity Models Required for Cascading Failure

Decrease high-temperature reaction rate by 2x again



- Propagation predictions will improve with fidelity of high-temperature chemistry